

SN74ALVCH162244

16-BIT BUFFER/DRIVER WITH 3-STATE OUTPUTS

SCES065D – JANUARY 1996 – REVISED JUNE 1999

- Member of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

NOTE: For tape and reel order entry:
The DGGR package is abbreviated to GR.

description

This 16-bit buffer/driver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH162244 is designed specifically to improve the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

The device can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. It provides true outputs and symmetrical active-low output-enable ($\overline{OE}$) inputs.

The outputs, which are designed to sink up to 12 mA, include equivalent 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162244 is characterized for operation from –40°C to 85°C.

DGG OR DL PACKAGE
(TOP VIEW)

$\overline{1OE}$	1	48	$\overline{2OE}$
1Y1	2	47	1A1
1Y2	3	46	1A2
GND	4	45	GND
1Y3	5	44	1A3
1Y4	6	43	1A4
V_{CC}	7	42	V_{CC}
2Y1	8	41	2A1
2Y2	9	40	2A2
GND	10	39	GND
2Y3	11	38	2A3
2Y4	12	37	2A4
3Y1	13	36	3A1
3Y2	14	35	3A2
GND	15	34	GND
3Y3	16	33	3A3
3Y4	17	32	3A4
V_{CC}	18	31	V_{CC}
4Y1	19	30	4A1
4Y2	20	29	4A2
GND	21	28	GND
4Y3	22	27	4A3
4Y4	23	26	4A4
$\overline{4OE}$	24	25	$\overline{3OE}$



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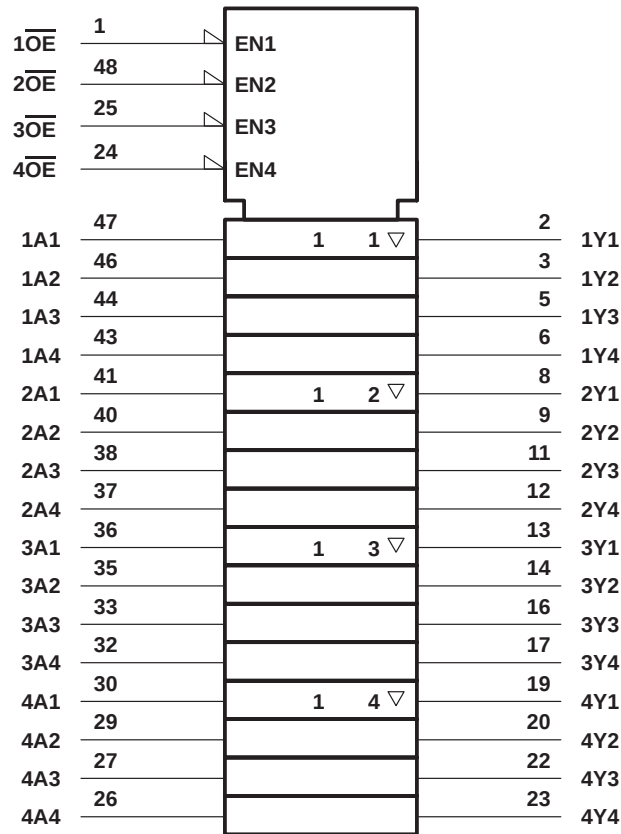
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FUNCTION TABLE
(each 4-bit buffer)

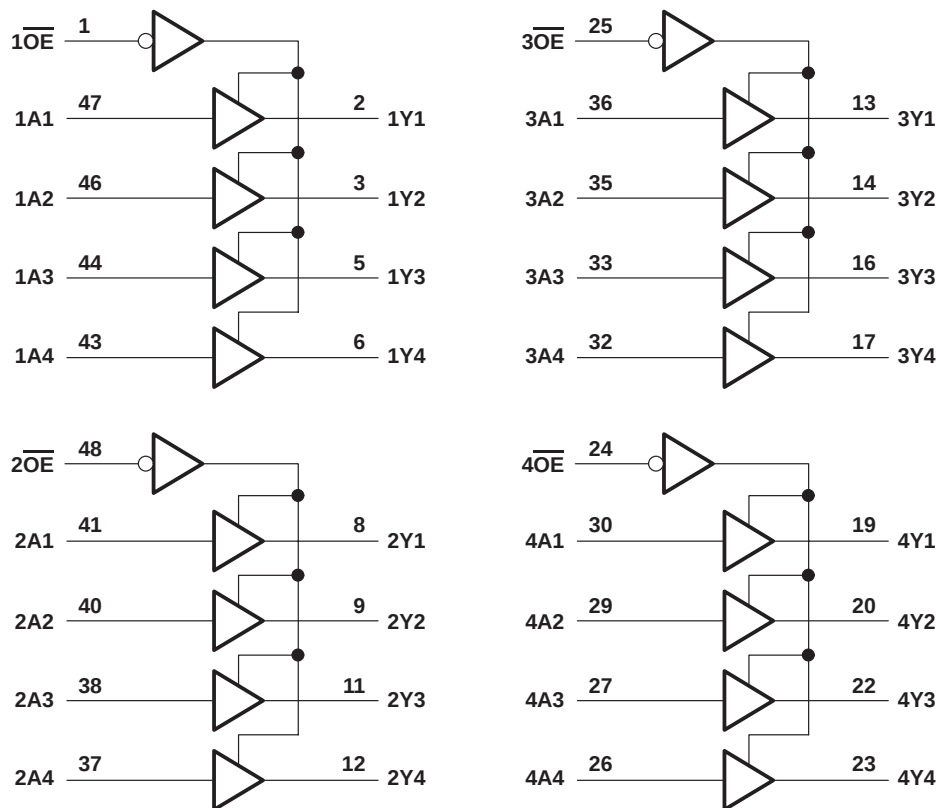
INPUTS		OUTPUT Y
$\overline{OE}$	A	
L	H	H
L	L	L
H	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Continuous output current, I_O	±50 mA
Continuous current through each V_{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 4.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	1.65	3.6	V
V_{IH}	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2	
V_{IL}	Low-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	0.8	
V_I	Input voltage	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	V
I_{OH}	High-level output current	$V_{CC} = 1.65 \text{ V}$	–2	mA
		$V_{CC} = 2.3 \text{ V}$	–6	
		$V_{CC} = 2.7 \text{ V}$	–8	
		$V_{CC} = 3 \text{ V}$	–12	
I_{OL}	Low-level output current	$V_{CC} = 1.65 \text{ V}$	2	mA
		$V_{CC} = 2.3 \text{ V}$	6	
		$V_{CC} = 2.7 \text{ V}$	8	
		$V_{CC} = 3 \text{ V}$	12	
$\Delta t/\Delta v$	Input transition rise or fall rate		10	ns/V
T_A	Operating free-air temperature	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP [†]	MAX	UNIT
V _{OH}		I _{OH} = –100 μA	1.65 V to 3.6 V	V _{CC} –0.2			V
		I _{OH} = –2 mA	1.65 V	1.2			
		I _{OH} = –4 mA	2.3 V	1.9			
		I _{OH} = –6 mA	2.3 V	1.7			
			3 V	2.4			
		I _{OH} = –8 mA	2.7 V	2			
		I _{OH} = –12 mA	3 V	2			
V _{OL}		I _{OL} = 100 μA	1.65 V to 3.6 V	0.2			V
		I _{OL} = 2 mA	1.65 V	0.45			
		I _{OL} = 4 mA	2.3 V	0.4			
		I _{OL} = 6 mA	2.3 V	0.55			
			3 V	0.55			
		I _{OL} = 8 mA	2.7 V	0.6			
		I _{OL} = 12 mA	3 V	0.8			
I _I		V _I = V _{CC} or GND	3.6 V	±5			μA
I _I (hold)		V _I = 0.58 V	1.65 V	25			μA
		V _I = 1.07 V	1.65 V	–25			
		V _I = 0.7 V	2.3 V	45			
		V _I = 1.7 V	2.3 V	–45			
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	–75			
		V _I = 0 to 3.6 V [‡]	3.6 V	±500			
I _{OZ}		V _O = V _{CC} or GND	3.6 V	±10			μA
I _{CC}		V _I = V _{CC} or GND, I _O = 0	3.6 V	40			μA
ΔI _{CC}		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V	750			μA
C _i	Control inputs	V _I = V _{CC} or GND	3.3 V	3			pF
	Data inputs			6			
C _O	Outputs	V _O = V _{CC} or GND	3.3 V	7			pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

[‡] This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
t _{pd}	A	Y	§	1	4.9	4.7		1	4.2	ns
t _{en}	$\overline{\text{OE}}$	Y	§	1	6.8	6.7		1	5.6	ns
t _{dis}	$\overline{\text{OE}}$	Y	§	1	6.3	5.7		1	5.5	ns

§ This information was not available at the time of publication.

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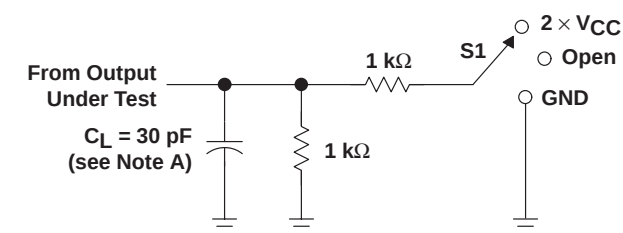
operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$	$V_{CC} = 2.5\text{ V}$	$V_{CC} = 3.3\text{ V}$	UNIT
			TYP	TYP	TYP	
C_{pd} Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}$, $f = 10\text{ MHz}$	†	16	19	pF
	Outputs disabled		†	4	5	

† This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V}$

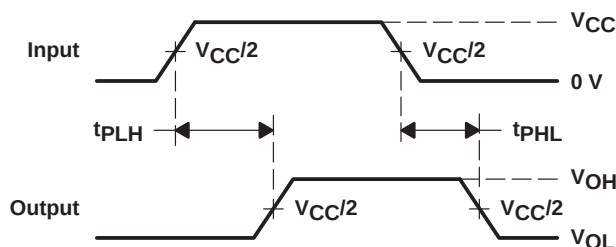


LOAD CIRCUIT

TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PHL}	GND



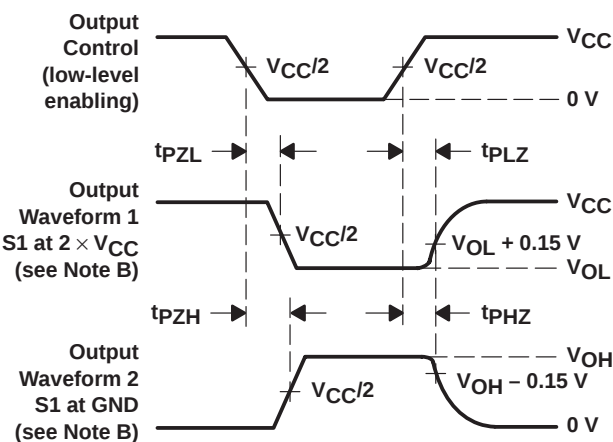
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

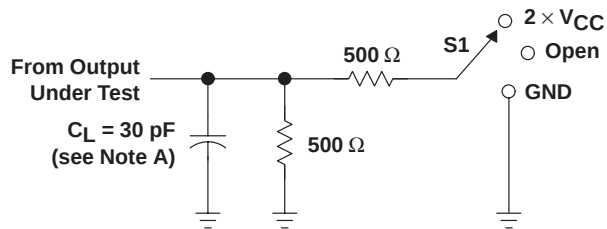
Figure 1. Load Circuit and Voltage Waveforms



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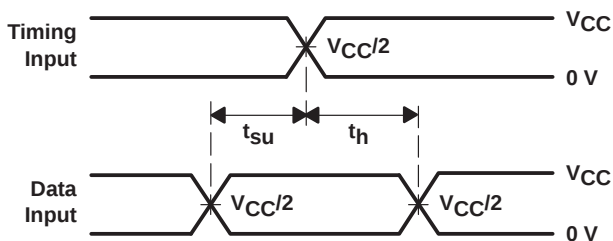
PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

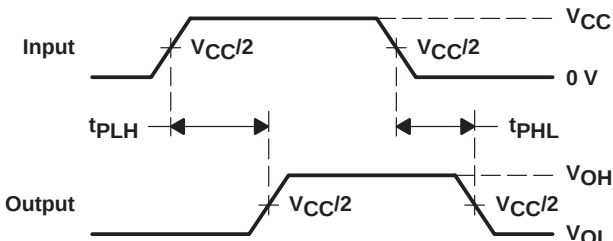


LOAD CIRCUIT

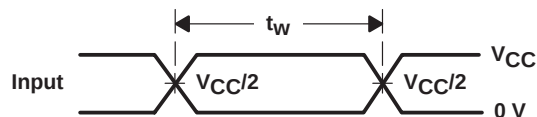
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND



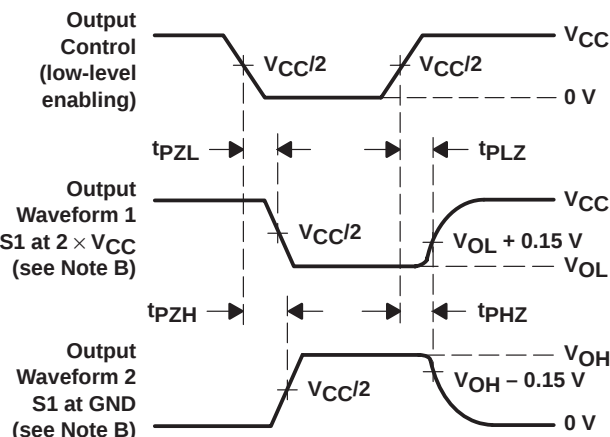
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 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

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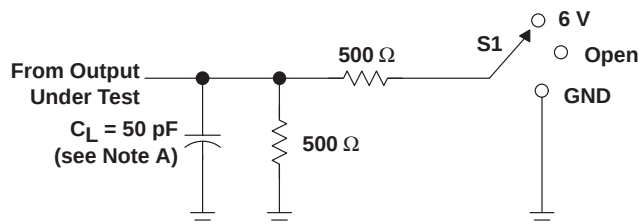
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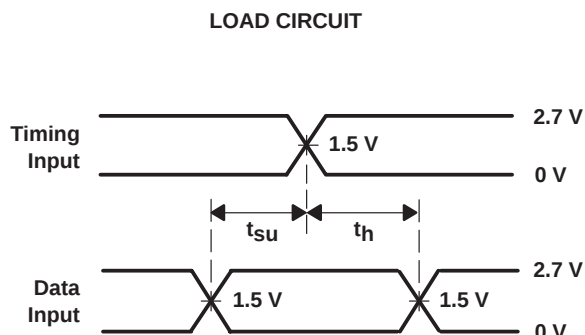
PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7 \text{ V AND } 3.3 \text{ V} \pm 0.3 \text{ V}$

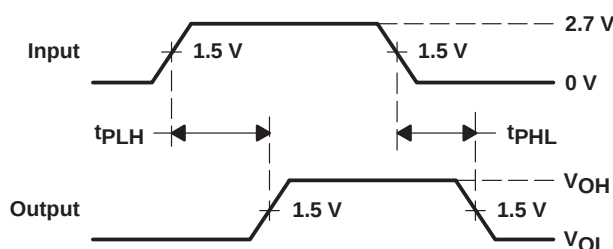


LOAD CIRCUIT

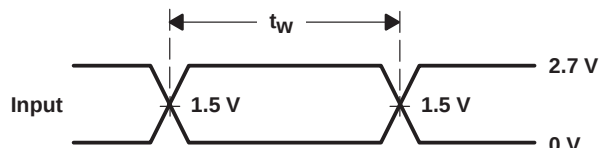
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND



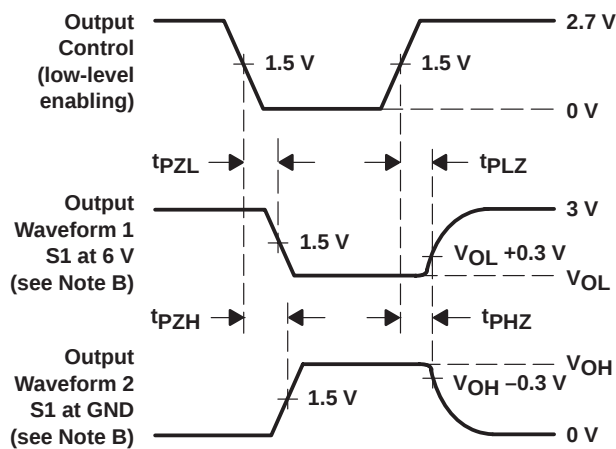
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 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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